Exciton Regeneration at Polymeric Sem iconductor Heterojunctions

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Abstract

Control of the band-edge o sets at heterojunctions between organic sem iconductors allows efcient operation of either photovoltaic or light-em itting diodes. We investigate systems where the exciton is marginally stable against charge separation, and show via E - eld-dependent timeresolved photolum inescence spectroscopy that excitons that have undergone charge separation at a heterojunction can be e ciently regenerated. This is because the charge transfer produces a gem inate electron-hole pair (separation 22{3.1 nm}) which may collapse into an exciplex and then endotherm ically ($E_A = 100{200 \text{ m eV}}$) back-transfer towards the exciton.

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E cient optoelectronic devices fabricated with sem iconductor polymers often employ heterojunctions between two components in which both the electron a nity and ionization potential are higher in one material than in the other (type II' heterojunctions, see inset of Fig. 1). This conguration is commonly used in photovoltaic diodes to achieve charge generation at the hetero-interface [1, 2, 3]. Typical devices involve a thin lm of a blend of hole-accepting and electron-accepting polymers sandwiched between two electrodes. However, some type II polymer blends show low photocurrents and high luminescence quantum yields, leading to very e cient light-emitting diodes [4, 5, 6, 7].

The high lum inescence quantum yield is commonly rationalized by the proposition that excitons can be stable at the hetero junction if their C oulom bic binding energy is higher than the band edge o sets [4]. In this case, the only process that m ight occur when an exciton encounters the hetero junction is energy transfer from the material with the larger band gap to the other component. This picture classi es type II hetero junctions into those above and those below a charge-separation threshold, producing high photocurrents or lum inescence quantum yields, respectively. This simple classi cation is incomplete because even system s that show high lum inescence e ciencies often also show signi cant charge generation (see below). By considering the dependence of photolum inescence spectra and dynamics on applied electric eld, we develop here an alternative, uni ed description of the excitation dynamics at the polymer heterojunction. We show that in all blends the exciton rst dissociates at the heterojunction and form s an interfacial gem inate charge pair. However, gem inate pair recombination via an intermediate hetero junction state (termed an exciplex) can regenerate the bulk exciton. These circular transitions between the di erent excited states at the hetero junction are driven by them alenergy, and a ne balance of the kinetics determ ines the net charge separation and photolum inescence yields.

Bulk excitons show relatively strong C oulom bic binding (of order 0.5 eV [4, 8]), and can be trapped at the hetero junction, acquiring som e charge-transfer character. Such excitations are term ed exciplexes when seen in isolated donor-acceptor systems and are characterized by featureless, red-shifted em ission spectra and long radiative decay times [9]. Recently, we have shown that exciplex states form in blends of F8BT with PFB, and F8BT with TFB (see Fig. 2 form olecular structures), and that these exciplex states can undergo endotherm ic energy transfer to form a bulk F8BT exciton [7]. Here we investigate Im sofPFB £8BT and TFB £8BT spin-coated from common chloroform solution. In general, there is substantial

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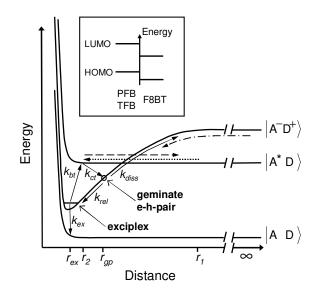


Figure 1: Potential energy diagram describing the energetics and kinetics at type II polymer heterojunctions. The energetic order of $\mathbf{\hat{A}}$ D⁺ $\mathbf{i}_{r=1}$ and $\mathbf{\hat{A}}$ D $\mathbf{i}_{r=1}$ may be reversed for PFB **F**8BT vs. TFB **F**8BT. The inset shows the band o sets at a type II heterojunction (see also [7]).

dem ixing of the two polymers through spinodal decomposition during drying, but under the rapid drying conditions achieved here there is more limited dem ixing (of the order of 10 nm [2]) resulting in a large interfacial area of contact between the two polymers. Note that PFB \pm 8BT blends can display high charge separation yields (4% photocurrent external quantum e ciency) and low EL e ciencies (< 0.64 lm/W) whereas the TFB \pm 8BT system displays low photocurrents (we nd 82% lower short-circuit current than in PFB \pm 8BT at 457 nm excitation), but very high electrolum inescence e ciencies (up to 19.4 lm/W) [7, 10]. Hence, these blends are good examples for the contrasting properties of type II polymer hetero junctions as described above.

For all m easurements, polymer blends (m ass ratio 1:1) were spin-coated from common chloroform solution onto oxygen-plasma-treated ITO substrates to form 170 nm thin lms. Ca electrodes (60 nm) were then deposited by thermal evaporation and encapsulated by a 300 nm Allayer. All devices were fabricated under N_2 atmosphere. An electric eld was applied by reverse-biasing the device to prevent charge injection (ITO negative with respect to Ca). Quasi-steady-state photolum inescence (PL) quenching m easurements were taken by exciting the sample with a CW Ar⁺ laser (457 nm) through the ITO. The resulting PL was in aged through a monochromator onto a Si photodiode. A modulated voltage was applied to the device and changes in PL due to the applied electric eld, PL, were detected using a lock-in ampli er referenced to the modulation frequency (225Hz). The total PL intensity was measured by mechanical modulation of the laser excitation. The results reported here are independent of modulation frequency and excitation power. T in e-resolved PL measurements were also performed using time-correlated single photon counting (TCSPC) and photolum inescence up-conversion (PLUC) spectroscopies with 70 ps and 300 fs time-resolution, respectively. Our TCSPC and PLUC setups are described elsewhere [7, 11]. All measurements were taken in continuous- ow He cryostats (Oxford Instruments OptistatCF) under inert conditions. Finally, PL e ciency measurements were performed on simple polymer thin Im s spin-coated on Spectroscil substrates using an integrating sphere coupled to an Oriel InstaSpec IV spectrograph and excitation with the same A r⁺ laser as above.

Fig. 2 (a) compares the PL spectrum of a diode m ade with blended PFB \pm 8BT with that of pure F8BT.Red-shifted exciplex emission, in addition to bulk F8BT contribution (i.e. the F8BT-only spectrum), is evident in the blend lm. (Neither PFB nor TFB are excited at 457 nm [10].) A loo shown in the same gure is the PL spectrum taken by applying 10V bias across the device. The electric eld preferentially quenches the exciplex contribution in the red part of the spectrum (> 50% quenching for wavelengths > 650 nm). Quenching of the F8BT exciton emission is also observed, but decreases with decreasing temperature, as demonstrated in Fig. 2 (b). Sim ilar phenom ena are observed in the TFB \pm 8BT diode (Figs. 2 (c) and 2 (d)), although the relative contribution of F8BT bulk emission is higher in the same temperature range. In contrast to the blends, pure F8BT does not show PL quenching (integrated PL/PL 1%) and only Stark-shifts by < 1nm at these elds.

If the PL quenching arises from eld-assisted dissociation of an emissive state, its luminescence decay rate should be eld-dependent. Fig. 3 (a) shows TCSPC measurements at 640 nm in a PFB #8BT diode with di erent applied voltages. All curves consist of an instrum ent-limited decay, and a slow, roughly mono-exponential decay with 40 5 ns time constant. The two components are assigned to the bulk exciton and the exciplex state, respectively [7]. Exciplex generation occurs within 1 ns and its generation e ciency is strongly eld-dependent, while its decay constant shows no signi cant variation with applied eld. Therefore, an exciplex precursor must be quenched by the eld. To investigate the eld dependence on the bulk exciton decay rate, we have perform ed eld-dependent PLUC

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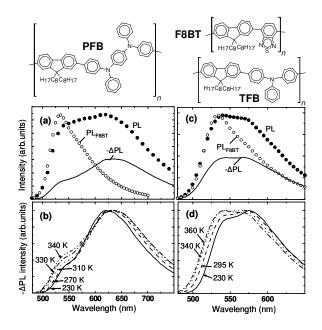


Figure 2: (a) Photolum inescence intensity (PL, solid circles) and reduction of photolum inescence intensity due to an applied reverse bias of 10V (PL, continuous line) for a PFB **F**8BT blend device at 340K.PL and PL are plotted in the sam e scale and re ect their relative intensities. (b) PL spectra (at 10V) from the sam e device as in (a) at di erent temperatures. (c) PL (solid circles) and PL at a reverse bias of 15V (continuous line) for a TFB **F**8BT blend device at 340K. (d) PL spectra from the sam e device as in (c) at di erent temperatures. For comparison the PL spectrum from an F8BT-only device (open circles) is plotted in both part (a) and (c). The structures of PFB, F8BT, and TFB are also shown.

m easurements. The results are displayed in Fig. 3(b). The exciton decay dynamics are not eld dependent [12]. Therefore, a dark intermediate state must be dissociated by the eld. We postulate that this state is an interfacial gem inate polaron pair that follows charge transfer from the bulk exciton [13, 14, 15, 16].

To estim ate the electron-hole separation within this gem inate pair, r_{gp} , we have investigated the eld-dependent changes in PL intensity (Fig. 4). Neglecting the electron of energetic disorder [17] and of a possible interfacial dipole layer [16], gem inate-pair dissociation in electric elds is most easily described within the Onsager model [18], which yields the dissociation probability f (r_{gp} ; T; F) = f (F) of bulk gem inate pairs in a medium with dielectric constant , under an applied eld F and at tem perature T [19]. Since the only material param eter is the dielectric constant, which we approxim ate to be 3.5 for all polymers, Onsager

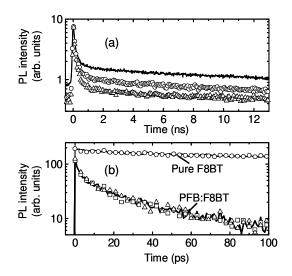


Figure 3: (a) Photolum inescence decay m easured using TCSPC (excitation: 407 nm, $< 4 \text{ nJ}=\text{cm}^2$, detection: 640 nm) from a PFB F8BT device at room temperature under 0V (continuous line), 13V (circles) and 30V (triangles) applied reverse biases. (b) PLUC m easurements (excitation: 405 nm, $42 \text{ nJ}=\text{cm}^2$, detection: 550 nm) from a similar device at 0V (continuous line), 5V (squares) and 12.5 V (triangles) reverse bias. For comparison, data for a device with pure F8BT at 0V (continuous line) and 12 V (circles) are also plotted.

theory should be applicable also to gem inate pairs at the interface. The eld-dependent relative reduction of the gem inate pair population n_{gp} is given by $\frac{n_{gp}}{n_{gp}} = \frac{f(F) f(0)}{1 f(0)}$. Fig. 4 plots $\frac{PL}{PL}$ versus electric eld [20] at various tem peratures for PFB F8BT and TFB F8BT devices (m easured in the red part of the spectrum where exciton em ission is insigni cant). P lotted in the same graph are simulations of $\frac{n_{gp}}{n_{gp}}$ using a -function distribution for r_{gp} . The simple m odel to the data satisfactorily, which supports the assumption of a gem inate pair intermediate prior to exciplex form ation and yields r_{gp} 3.1 nm (PFB F8BT) and r_{gp} 2.2 nm (TFB F8BT). The large separation is probably caused by polaron-pair therm alization follow ing the initial charge-transfer step [13, 18].

We now return to the PL spectra in Fig. 2, which contain bulk F8BT components that are not due to electric- eld promoted dissociation of those states as was shown above. The zero- eld steady-state photolum inescence is due to three di erent excited-state populations: (i) \prim ary" excitons, generated in the bulk by the laser excitation; (ii) exciplexes, generated via energy transfer from bulk excitons; and (iii) \secondary" excitons, generated via endotherm ic back-transfer from the exciplexes [7]. Since the exciplex density is reduced

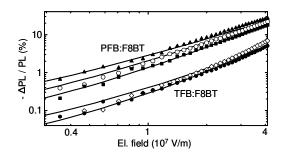


Figure 4: Relative electric eld quenching of the PFB \pm 8BT and TFB \pm 8BT exciplex photolum inescence intensities (m easured at 700 nm and 580 nm, respectively), in the same devices as in Fig. 2, versus electric eld at 230 K (solid squares), 250 K (open and solid circles), 290 K (solid triangles) and 295 K (open diam onds). The solid lines through the data are 0 nsager simulations (param eters for PFB \pm 8BT: = 3:5, r_{gp} = 3:0 nm at T = 230 K and 3.1 nm at 250 K and 290 K; for TFB \pm 8BT: = 3:5, r_{gp} = 2:3 nm at T = 250 K and 2.2 nm at 295 K).

by application of an electric eld, there is less secondary exciton generation, and hence the observed PL contains an excitonic contribution. Further evidence for this hypothesis is provided by the temperature dependence of the PL spectra shown in Figs. 2 (b) and 2 (d) [21]. The ratio of secondary excitons to exciplexes is found to follow an Arrhenius function with activation energy 200 50m eV (PFB \pm 8BT) and 100 30m eV (TFB \pm 8BT). These activation energies are consistent with those values extracted with our previous TC – SPC m easurem ents [7].

Fig.1 sum marizes the above ndings. The potential energy curves represent the ground state (AD i), the exciton residing on F8BT (A D i), and the electron and the hole residing in the respective component across the hetero junction (A D⁺ i), where A and D symbolize the acceptor (F8BT) and the donor (PFB or TFB), respectively. The abscissa represents the interm olecular distance, i.e. either the distance of the exciton from the interface or the separation of the gem inate polarons. The exciplex state is then located in the m inim um of the A D⁺ i potential. W hen the system is photoexcited, an exciton is generated at a certain distance r_1 from the hetero junction. It then di uses to a separation r_2 (dotted arrow), where it dissociates and an interfacial gem inate electron-hole pair is form ed with rate constant k_{ct} . This gem inate pair can either dissociate (k_{diss}) or relax into the lum inescent exciplex state (k_{rel}). The ratio $k_{diss}=k_{rel}$ is strongly eld dependent and determ ines the degree of lum inescence quenching. The exciplex state can then either decay (k_{ex}), or back-transfer to

a bulk exciton in F8BT (k_{bt}), but is itself too strongly bound to dissociate under the eld. We note that the transition from gem inate pairs to excitons via k_{rel} ! k_{bt} represents a novel mechanism for gem inate pair recombination at polymeric heterojunctions. The secondary excitons produced might enter the cycle again, or di use away from the heterojunction (dashed arrow) and decay. The model is also applicable to electrical excitation, where the excited state is produced via charge injection (dash-dotted arrow). The regeneration of the exciton via the thermally-driven circular process k_{ct} ! k_{rel} ! k_{bt} means that even though charge transfer occurs, the excitation energy might eventually still be emitted in the form of bulk exciton lum inescence.

An estimate of the contribution of the regeneration process to the PL of the blend can be derived by normalizing the PL spectrum to the PL spectrum at higher wavelengths where the emission is solely due to exciplexes. We assume that this re-normalized PL then represents the contribution of exciplex and secondary exciton emission to the total PL.We infer thereby that at room temperature in the PFB \pm 8BT blend 20% of the visible emission comes from primary excitons. In TFB \pm 8BT we nd a primary exciton contribution of < 2%, which implies that > 98% of the excitons undergo charge transfer at a hetero junction. Despite that, the relative PL quenching with respect to pure \pm 8BT is only < 57% (PL yield of \pm 8BT 80%, of TFB \pm 8BT 35%) indicating the great in portance of the exciton regeneration mechanism. Secondary exciton and exciplex emission maintain a high PL yield in spite of most excitons encountering a hetero junction. On the other hand, the PFB \pm 8BT PL yield is only 4%, consistent with large geminate pair dissociation and low back-transfer e ciency, i.e. with low \regeneration e ciency".

In sum mary, we have developed a comprehensive description of the excitonic and electronic processes at type-II polymer heterojunctions that support exciplex formation. The two blends studied here represent in portant examples for elected tharge generation on the one hand and high lum inescence yields on the other, and in this sense represent the two extremes of type-II heterojunctions found in common sem iconductor polymer blends. The very dient behavior was shown to arise from dienent geminate pair separations (3.1 nm vs. 2.2 nm) and back-transfer activation energies (200 meV vs. 100 meV) which a lect strongly the kinetics between the states involved. We note that both them alization distance as well as activation energy are generally expected to be larger for larger band edge oligies of sets between the two polymers and that this provides the link to the classic cation scheme described in

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the introduction [4]. G iven that excited-state electronic dimens are commonly observed in polymeric sem iconductors [22], we consider exciplex formation and exciton regeneration to also be general phenomena at type II polymeric hetero junctions. As shown in this letter, the central role of these dynamics is not directly evident from steady-state PL measurements if back-transfer is e-cient.

In photovoltaic operation the collapse of the gem inste pair into the exciplex provides an unwanted loss channel. We suggest that optimized interfaces require not only large band-edge o sets to enable large therm alization distances (r_{gp}) , but also inhibited exciplex stabilization. This can be achieved by increasing interm olecular distances and decreasing con gurational relaxation [9].

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